



**INFORMATION DISCLOSURE CITATION
IN AN APPLICATION**
(Use several sheets if necessary)

PTO Form 1449

Atty Docket No. 112857-315	Application No. 10/062,776
Applicant Yoshiyuki Yanagisawa et al.	
Filing Date 01/30/2002	Group 2812

U.S. PATENT DOCUMENTS

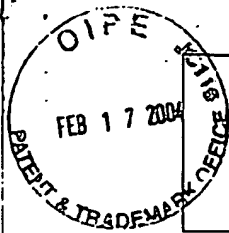
Examiner's Initials	Document Number	Publication Date	Inventor	Class	Subclass	Filing Date If Appropriate
GJM	5,177,405	01/05/1993	Kusuda et al.			
	5,206,749	04/27/1993	Zavracky et al.			
	5,258,320	11/02/1993	Zavracky et al.			
	5,438,241	08/01/1995	Zavracky et al.			
	5,739,800	04/14/1998	Lebby et al.			
GJM	5,981,977	11/09/1999	Furukawa et al.			

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Examiner's Initials	Document Number	Publication Date	Country	Class	Subclass	Translation	
						Yes	No
GJM	56-17385 ✓	02/19/1981	Japan				
	56-92577 ✓	07/27/1981	Japan				
	57-45583 ✓	03/15/1982	Japan				
	57-52071 ✓	03/27/1982	Japan				
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	57-52073 ✓	03/27/1982	Japan				
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	63-188938 ✓	08/04/1988	Japan				
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	04-010671	01/14/1992	Japan				
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	05-290669 ✓	11/05/1993	Japan				
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06-067044	03/11/1994	Japan					
06-504139	05/12/1994	Japan					

Examiner: GJM Date Considered: 3/16/02

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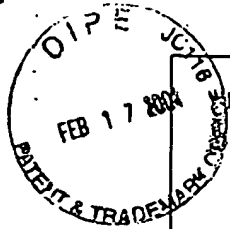
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						Yes	No
GM	WO 95-05623	02/23/1995	PCT				
	07-199829	04/08/1995	Japan				
	07-110660	04/25/1995	Japan				
	07-263754	10/13/1995	Japan				
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	11-251253	09/17/1999	Japan				
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GM	11-514136	11/30/1999	Japan				

Examiner: <i>S. A. ...</i>	Date Considered: 2/11/02
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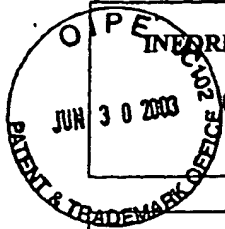


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GJ	11-346004	12/14/1999	Japan				
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	2001-217503	08/10/2001	Japan				
	2002-185660	12/12/2002	Japan				

Examiner's Initials	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)
GJ	Zheleva et al., "Pendeo/Epitaxy - A New Approach For Lateral Growth Of Gallium Nitride Structures", MRS Internet J. Nitride Semicond. Res. 4S1, G3.38 (1999).
	Kapolnek et al., "Spatial Control Of InGaN Luminescence By MOCVD Selective Epitaxy, Journal Of Crystal Growth", 189/190 (1998) pp. 83/86.
SN	Applied Physics Letters, Vol. 76, Number 22, 29 May 2000, "Selective Growth Of InGaN Quantum Dot Structures And Their Microphotoluminescence At Room Temperature". Tachibani et al, pages 3212/3214

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	A2						
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	A7						
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	A9						
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SM	A13 JP 5-315646	11/26/1993	Japan				
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	A16						
	A17						
	A18						
	A19						
	A20						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner's Initials	
	A21
	A22
	A23
	A24
	A25

Examiner: <i>S. M. [Signature]</i>	Date Considered: <i>12/15/03</i>
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